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Search Notes		

	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/813,129	HIRAMATSU ET AL.	AMATSU ET AL.
	Examiner	Art Unit	Unit
_	Hiep Nguyen	2816	6

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INTERFERENCE SEARCHED			
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PG PUB	Search	06.06 86	18

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